

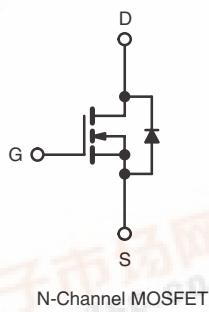
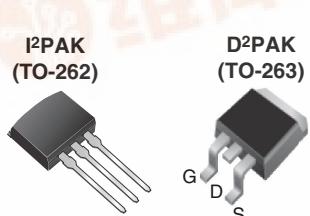


IRF840AS, IRF840AL, SiHF840AS, SiHF840AL

Vishay Siliconix

Power MOSFET

PRODUCT SUMMARY	
V _{DS} (V)	500
R _{DS(on)} (Ω)	V _{GS} = 10 V 0.85
Q _g (Max.) (nC)	38
Q _{gs} (nC)	9.0
Q _{gd} (nC)	18
Configuration	Single



FEATURES

- Low Gate Charge Q_g Results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Effective C_{oss} Specified
- Lead (Pb)-free Available

RoHS*
COMPLIANT

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply
- High Speed Power Switching

TYPICAL SMPS TOPOLOGIES

- Two Transistor Forward
- Half Bridge
- Full Bridge

ORDERING INFORMATION				
Package	D²PAK (TO-263)	D²PAK (TO-263)	D²PAK (TO-263)	I²PAK (TO-262)
Lead (Pb)-free	IRF840ASPBf	IRF840ASTRLPbF ^a	IRF840ASTRRPbF ^a	IRF840ALPbF
	SiHF840AS-E3	SiHF840ASTL-E3 ^a	SiHF840ASTR-E3 ^a	SiHF840AL-E3
SnPb	IRF840AS	IRF840ASTRL ^a	IRF840ASTRR ^a	IRF840AL
	SiHF840AS	SiHF840ASTL ^a	SiHF840ASTR ^a	SiHF840AL

Note

- a. See device orientation.

ABSOLUTE MAXIMUM RATINGS T_C = 25 °C, unless otherwise noted

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V _{DS}	500	V
Gate-Source Voltage	V _{GS}	± 30	
Continuous Drain Current	I _D	8.0 5.1	A
Pulsed Drain Current ^a	I _{DM}	32	
Linear Derating Factor		1.0	W/°C
Single Pulse Avalanche Energy ^b	E _{AS}	510	mJ
Repetitive Avalanche Current ^a	I _{AR}	8.0	A
Repetitive Avalanche Energyc	E _{AR}	13	mJ
Maximum Power Dissipation	P _D	125 3.1	W
Peak Diode Recovery dV/dt ^{c, e}	dV/dt	5.0	V/ns
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to + 150	°C
Soldering Temperature	for 10 s	300 ^d	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Starting T_J = 25 °C, L = 16 mH, R_G = 25 Ω, I_{AS} = 8.0 A (see fig. 12).
c. I_{SD} ≤ 8.0 A, dI/dt ≤ 100 A/μs, V_{DD} ≤ V_{DS}, T_J ≤ 150 °C.
d. 1.6 mm from case.
e. Uses IRF840A/SiHF840A data and test conditions.

* Pb containing terminations are not RoHS compliant, exemptions may apply



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THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient (PCB Mount) ^a	R _{thJA}	-	-	40	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	-	1.0	

Note

- a. When mounted on 1" square PCB (FR-4 or G-10 material).

SPECIFICATIONS T_J = 25 °C, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA		500	-	-	V
V _{DS} Temperature Coefficient	ΔV _{DS} /T _J	Reference to 25 °C, I _D = 1 mA ^d		-	0.58	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA		2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 30 V		-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 500 V, V _{GS} = 0 V		-	-	25	μA
		V _{DS} = 400 V, V _{GS} = 0 V, T _J = 125 °C		-	-	250	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 4.8 A ^b	-	-	0.85	Ω
Forward Transconductance	g _{fs}	V _{DS} = 50 V, I _D = 4.8 A		3.7	-	-	S
Dynamic							
Input Capacitance	C _{iss}	V _{GS} = 0 V, V _{DS} = 25 V, f = 1.0 MHz, see fig. 5		-	1018	-	pF
Output Capacitance	C _{oss}			-	155	-	
Reverse Transfer Capacitance	C _{rss}			-	8.0	-	
Output Capacitance	C _{oss}	V _{GS} = 0 V	V _{DS} = 1.0 V, f = 1.0 MHz		1490		
Output Capacitance	C _{oss}		V _{DS} = 400 V, f = 1.0 MHz		42		
Effective Output Capacitance	C _{oss eff.}		V _{DS} = 0 V to 480 V ^{c, d}		56		
Total Gate Charge	Q _g	V _{GS} = 10 V	I _D = 8.0 A, V _{DS} = 400 V, see fig. 6 and 13 ^{b, d}	-	-	38	nC
Gate-Source Charge	Q _{gs}			-	-	9.0	
Gate-Drain Charge	Q _{gd}			-	-	18	
Turn-On Delay Time	t _{d(on)}	V _{DD} = 250 V, I _D = 8.0 A, R _G = 9.1 Ω, R _D = 31 Ω, see fig. 10 ^{b, d}		-	11	-	ns
Rise Time	t _r			-	23	-	
Turn-Off Delay Time	t _{d(off)}			-	26	-	
Fall Time	t _f			-	19	-	
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode	I ^D	-	-	8.0	A
Pulsed Diode Forward Current ^a	I _{SM}		I _S	-	-	32	
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 8.0 A, V _{GS} = 0 V ^b		-	-	2.0	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 8.0 A, dI/dt = 100 A/μs ^b		-	422	633	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	2.0	3.0	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)					

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width ≤ 300 μs; duty cycle ≤ 2 %.
- c. C_{oss eff.} is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80 % V_{DS}.
- d. Uses IRF840A/SiHF840A data and test conditions



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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

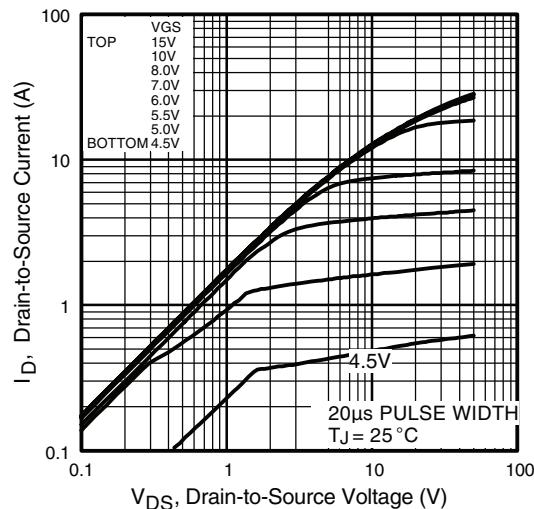


Fig. 1 - Typical Output Characteristics

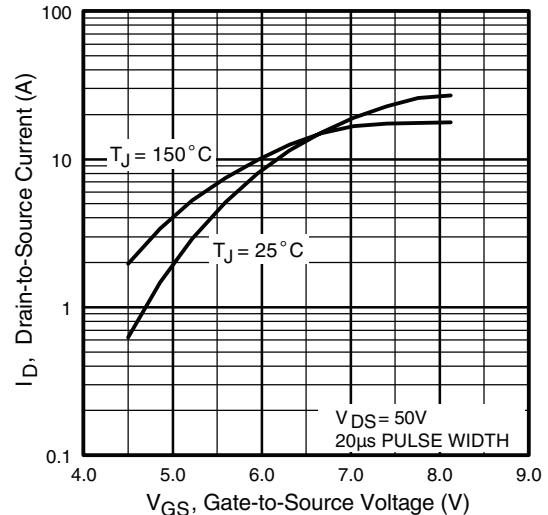


Fig. 3 - Typical Transfer Characteristics

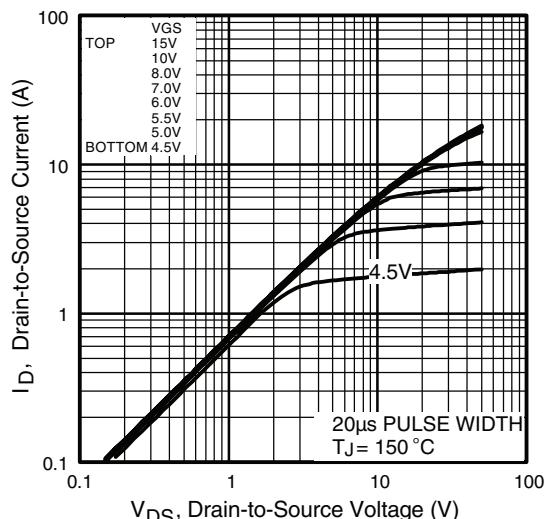


Fig. 2 - Typical Output Characteristics

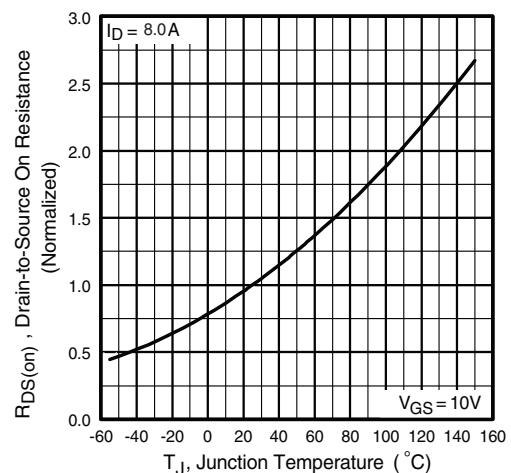


Fig. 4 - Normalized On-Resistance vs. Temperature

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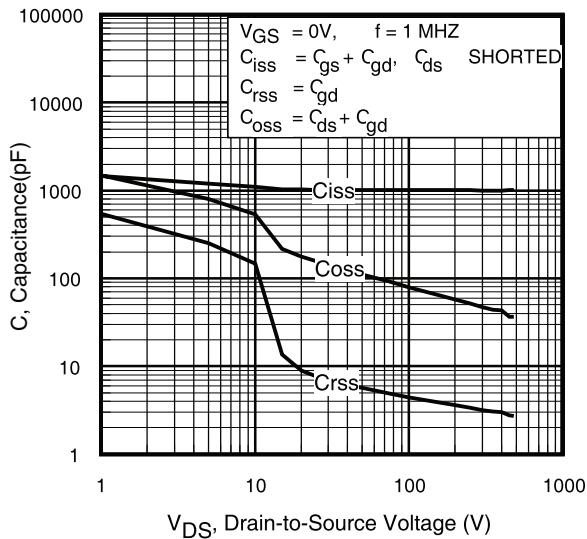


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

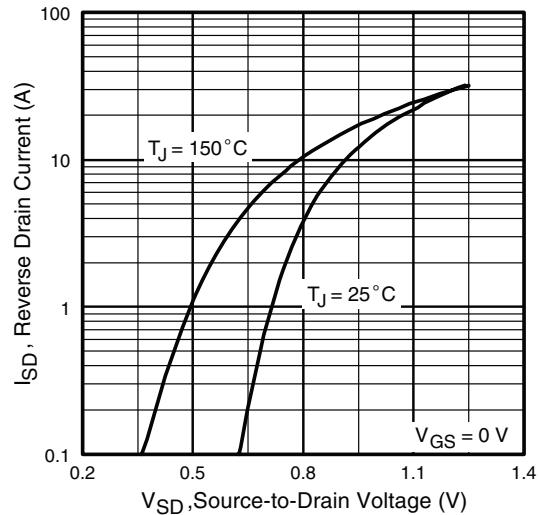


Fig. 7 - Typical Source-Drain Diode Forward Voltage

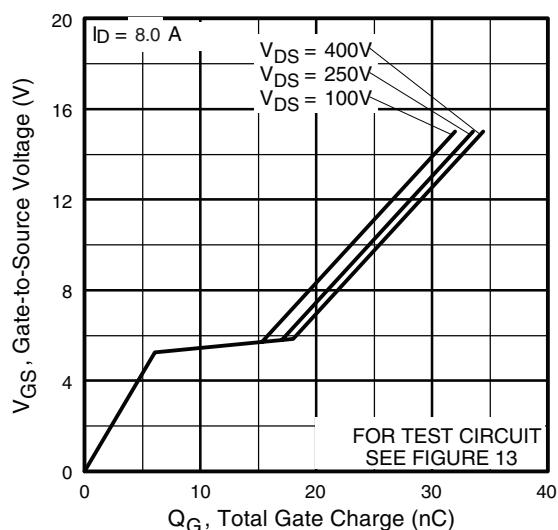


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

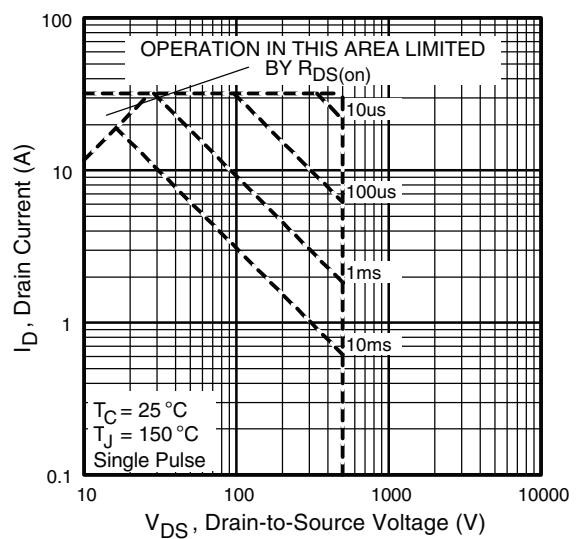


Fig. 8 - Maximum Safe Operating Area



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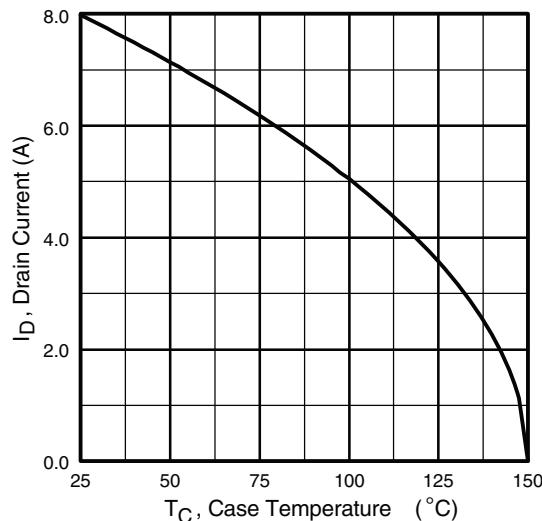


Fig. 9 - Maximum Drain Current vs. Case Temperature

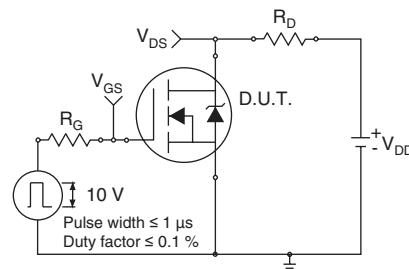


Fig. 10a - Switching Time Test Circuit

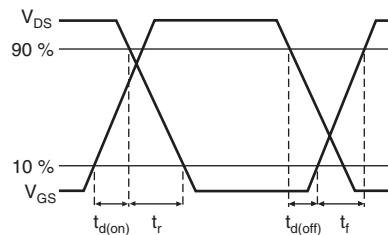


Fig. 10b - Switching Time Waveforms

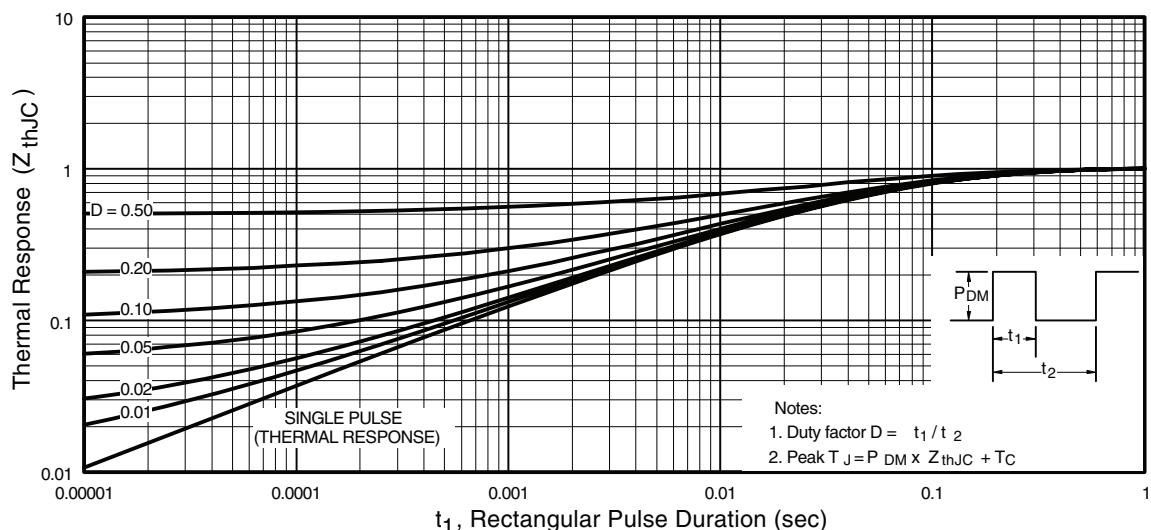


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

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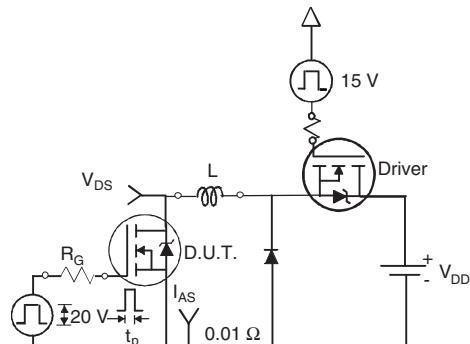


Fig. 12a - Unclamped Inductive Test Circuit

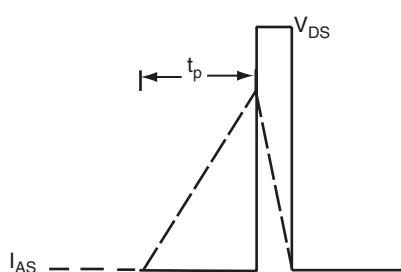


Fig. 12b - Unclamped Inductive Waveforms

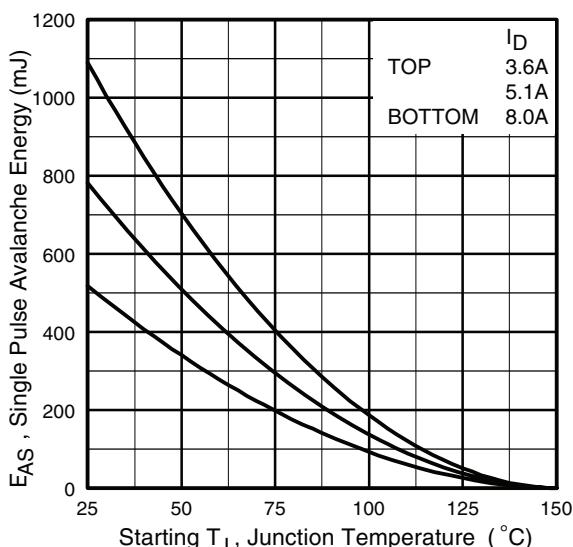


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

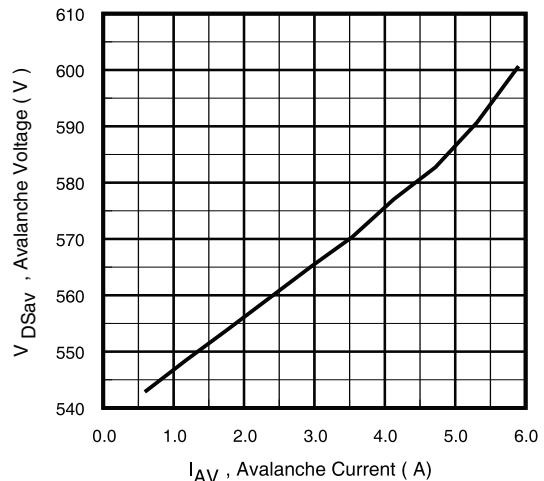


Fig. 12d - Typical Drain-to-Source Voltage vs. Avalanche Current

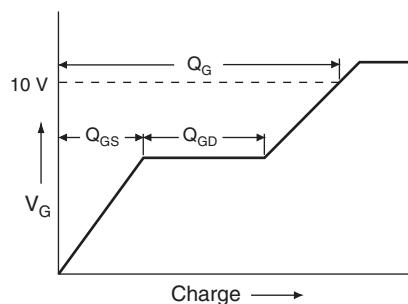


Fig. 13a - Basic Gate Charge Waveform

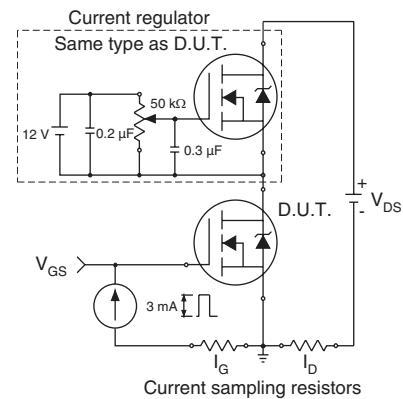


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit

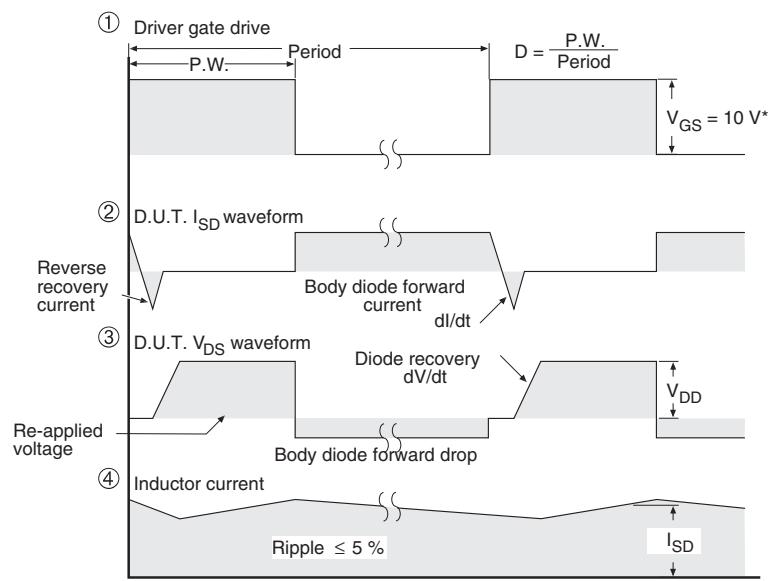
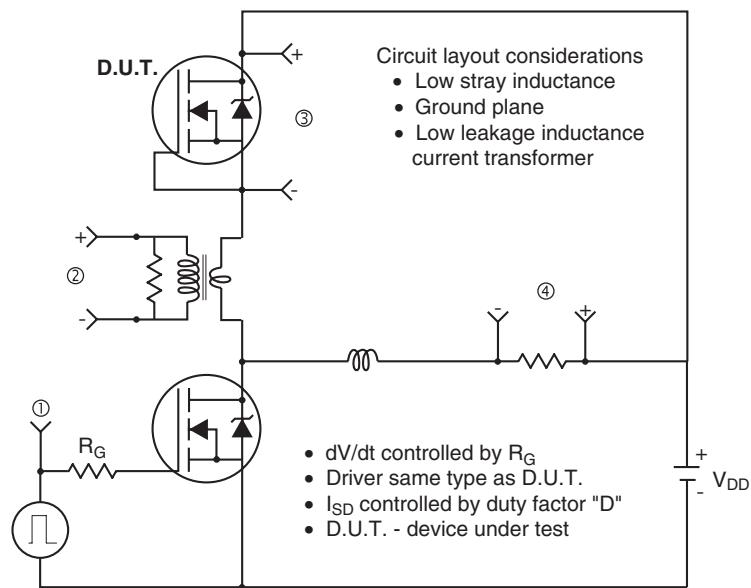


Fig. 14 - For N-Channel



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